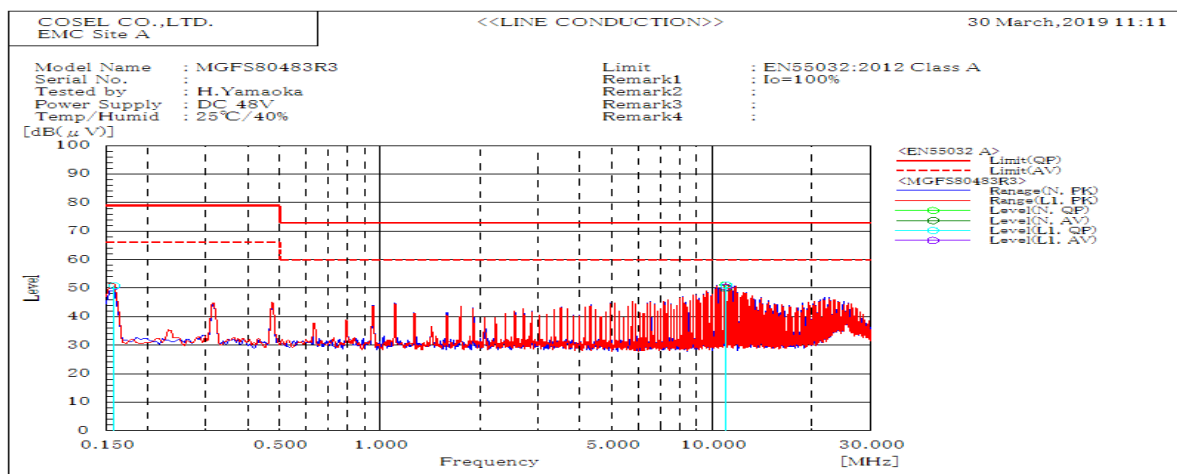
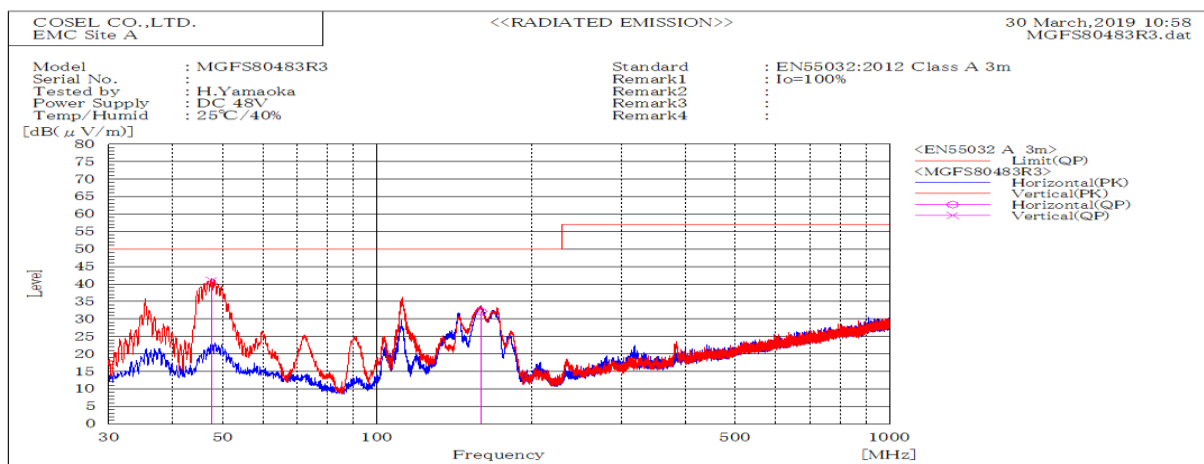


DATA SHEET		Date	23-Apr-19
Model	MGFS80483R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Yamaoka



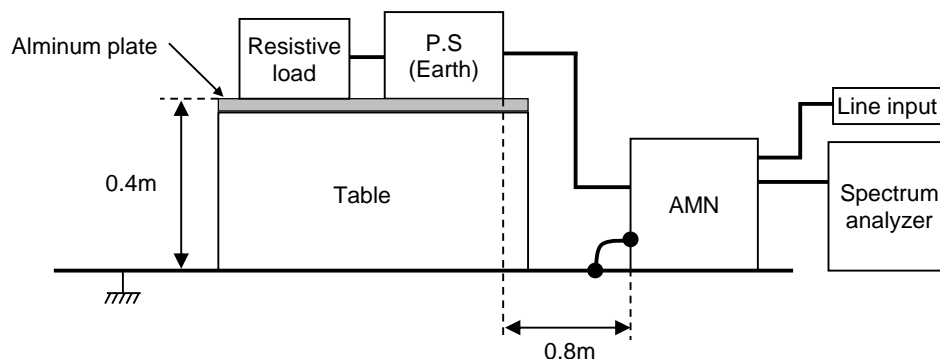
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
10.982	L1	51.1	50.4	73	60	21.9	9.6	Pass	
0.159	L1	50.9	50.8	79	66	28.1	15.2	Pass	
10.972	N	51.2	50	73	60	21.8	10	Pass	



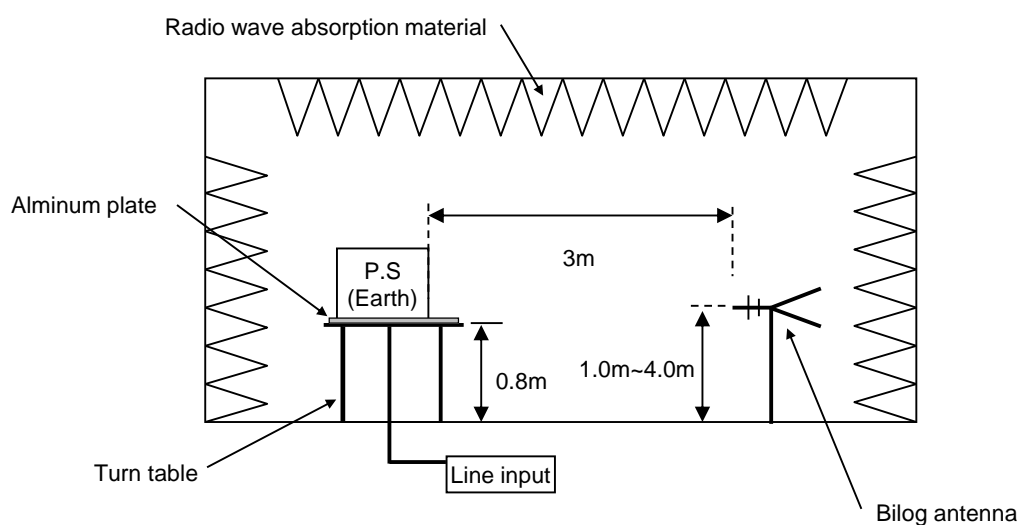
Frequency	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height	Angle	Remark
MHz			dB(μV/m)	dB(μV/m)	dB				
			QP	QP	QP				
159.583	H	Stable	32.2	50	17.8	Pass	179.6	154.4	
47.629	V	Stable	41	50	9	Pass	100.2	180.7	

DATA SHEET		Date	23-Apr-19
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Yamaoka

1. Line conduction



2. Radiated emission



Conditions

Test : EMI

Model Name : MGFS80□□

○Photographs of Test Set-Up LINE CONDUCTION



○Testing circuitry

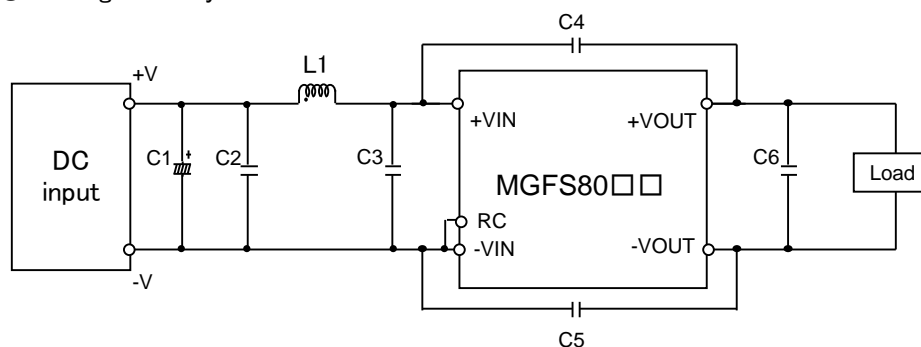


Fig.1 Testing circuitry

- C1 : MGFS8024□□ 63V 470 μ F Electrolytic capacitor (ELXZseries NIPPON CHEMI-CON)
MGFS8048□□ 100V 220 μ F Electrolytic capacitor (KYseries NIPPON CHEMI-CON)
- C2 : MGFS8024□□ 50V 10 μ F Ceramic capacitor (GRM32ER71H106K MURATA MANUFACTURING)
MGFS8048□□ 100V 4.7 μ F Ceramic capacitor (HMK325C7475K TAIYOU YUDEN)
- C3 : MGFS8024□□ 50V 10 μ F Ceramic capacitor (GRM32ER71H106K MURATA MANUFACTURING)
MGFS8048□□ 100V 4.7 μ F Ceramic capacitor (HMK325C7475K TAIYOU YUDEN)
- C4,C5 : MGFS8024□□ 2kV 2200pF Ceramic capacitor
(GR443QR73D222KW01 MURATA MANUFACTURING)
MGFS8048□□ 2kV 3300pF Ceramic capacitor
(GR443QR73D332KW01 MURATA MANUFACTURING)
- C6 : MGFS8024□□ 25V 22 μ F Ceramic capacitor (GRM32ER71E226K MURATA MANUFACTURING)
MGFS8048□□ 25V 22 μ F Ceramic capacitor (GRM32ER71E226K MURATA MANUFACTURING)
- L1 : MGFS8024□□ 12.0A 1.8 μ H Inductor (SRP7050TA-1R8M BOURNS)
MGFS8048□□ 8.0A 3.3 μ H Inductor (SRP7050TA-3R3M BOURNS)